

Rula Tawalbeh, David Voelz, David Glenar, Xifen Xiao, and Nancy Chanover, "AOTF Reflectance Spectroscopy: A diagnostic of organically modified surfaces", OSA, Applied Industrial Optics: *Spectroscopy, Imaging and Metrology meeting*, Tucson, AZ, June 7(2010).

A compact AOTF-based point spectrometer that operates at room temperature is described for measuring reflectance spectra over the 1.7 to 3.4 μm range. It provides "quick look" in situ detection of organically modified surfaces.